

Docket No. YOR920030175US1

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application

Applicant(s): Allen et al.
Case: YOR920030175US1
Serial No.: 10/661,041
Filing Date: September 12, 2003
Group: 2811
Examiner: Cuong Q. Nguyen

Title: Techniques for Patterning Features in Semiconductor Devices

AFFIDAVIT UNDER 37 C.F.R. §1.131

We, the undersigned, hereby declare and state as follows:

1. We are the named inventors of the above-referenced U.S. patent application.
2. On or around November, 2000, we prepared the enclosed document (labeled "Exhibit 1") that evidences a reduction to practice of an invention falling within one or more of the claims of the above-referenced application.
3. On page 3 of the document, an image is shown (situated on the left-hand side of page 3) (hereinafter "the image") that illustrates etching through a photoresist layer (top layer), an antireflective material layer (middle layer) and a portion of a substrate layer (lower layer).
4. As is shown in the image, a critical dimension reduction occurred during etching of the antireflective material layer. This is further evidenced by the caption to the image, which indicates a -30 nanometer critical dimension bias.

5. As shown in the image, critical dimension reduction occurred during etching of the antireflective material layer, as etching is shown to have ceased just following passage through the antireflective material layer.

6. All statements made herein of our own knowledge are true, and all statements made on information and belief are believed to be true.

7. We understand that willful false statements and the like are punishable by fine or imprisonment, or both, under 18 U.S.C. §1001, and may jeopardize the validity of the application or any patent issuing therefrom.

Date: _____

Scott D. Allen

Date: _____

Katherina E. Babich

Date: _____

Steven J. Holmes

Date: _____

Arpan P. Mahorowala

Date: _____

Dirk Pfeiffer

Date: _____

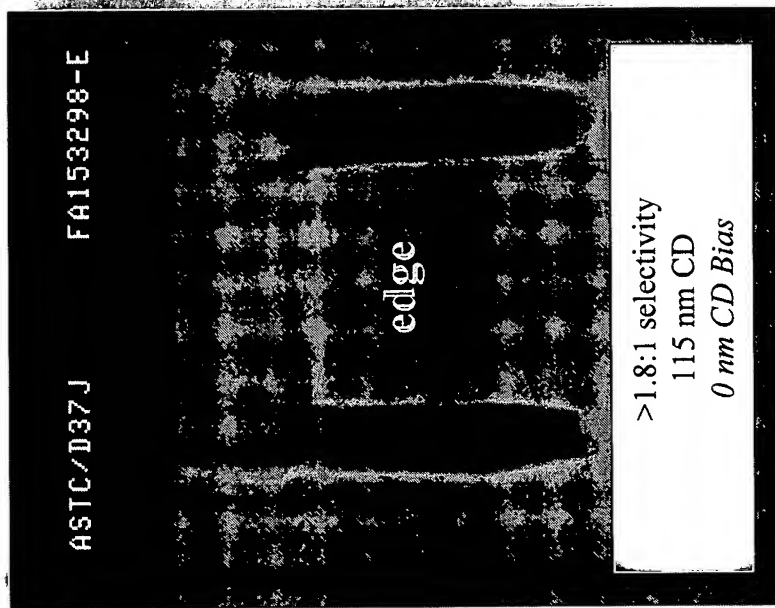
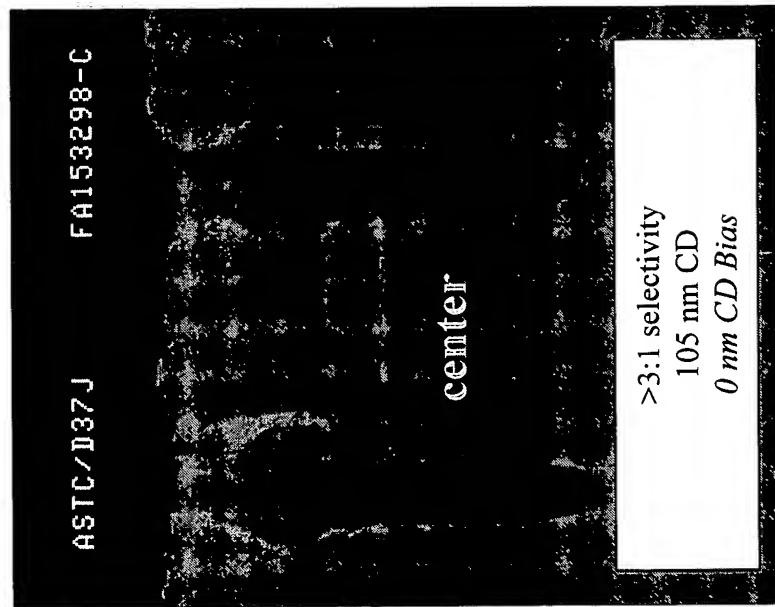
Richard Stephan Wise

DRAM DEVELOPMENT ALLIANCE

PAR-710 Resist (350 nm post develop) 300 nm TERA

TERA Development

Fluorocarbon Open Etch Processes - CHF₃ Base



TEL 85 Process:

SiC: 60 secs / 40 mT / 1.4kW / 5 C₄F₈ / 10 CHF₃ / 100 N₂ / 5 O₂ / 150 Ar

- => Increase τ_{RES} results in much improved c/e distribution, lower overall selectivity
- => Too much polymer in center, decrease τ_{RES} to improve profile (CGF system)

DRAM DEVELOPMENT ALLIANCE

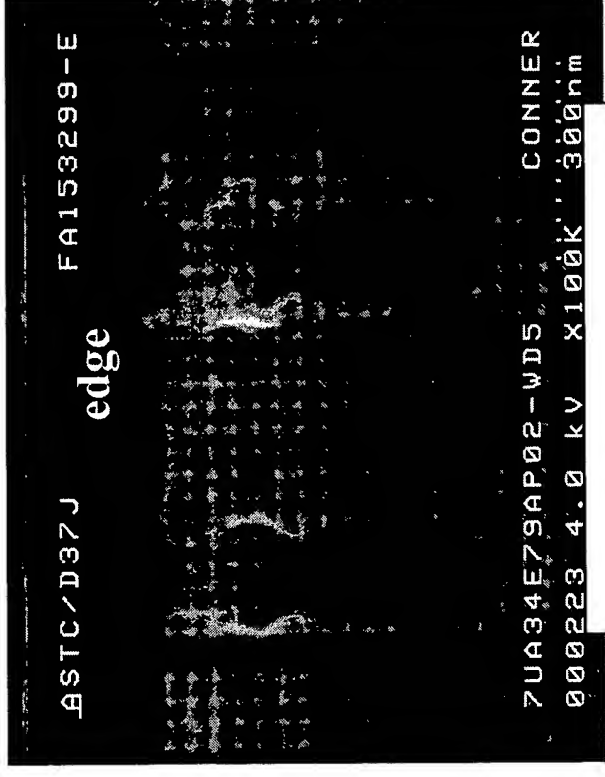
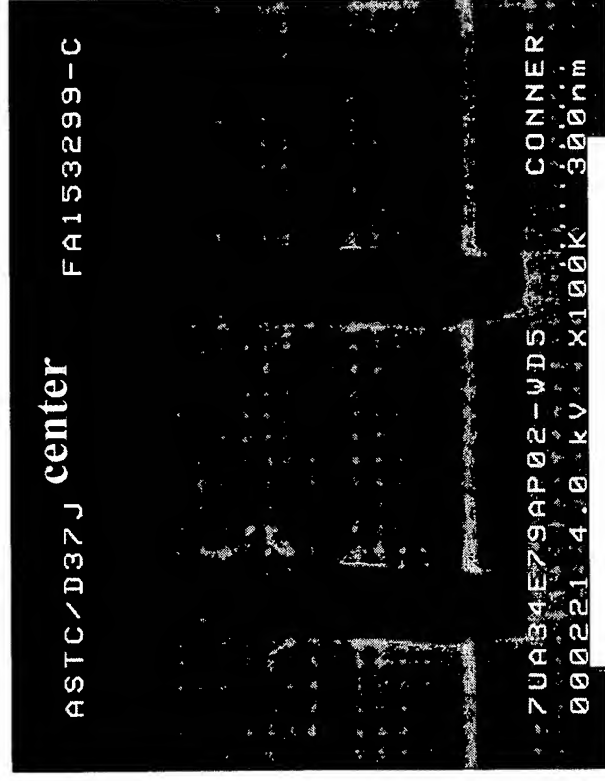
PAR-710 Resist

(350 nm post develop)

300 nm TERA

TERA Development

Fluorocarbon Open Etch Processes - CH_2F_2 Base



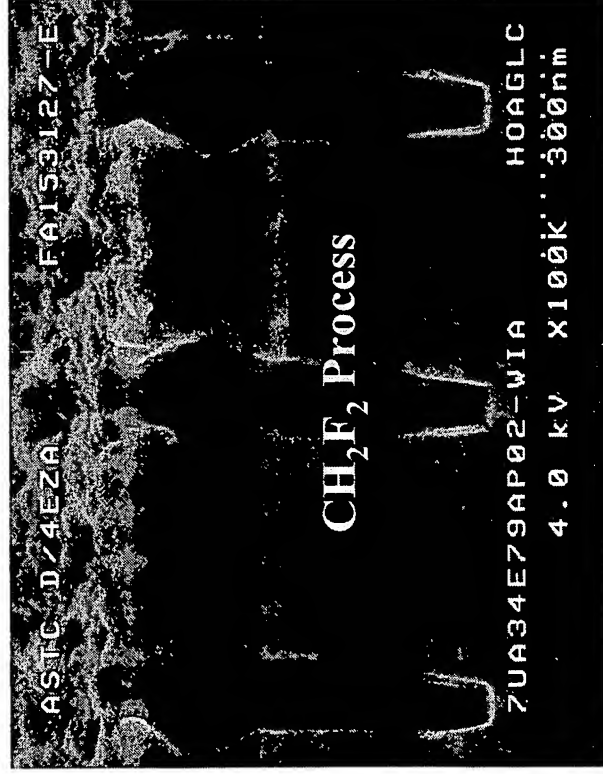
TEL 85 Process:

SiC: 60 secs / 40 mT / 1.4kW / 4 C_4F_8 / 10 CH_2F_2 / 100 N_2 / 5 O_2 / 200 Ar

- => Addition of 20% N_2 , reduction 20% C_4F_8 to CH_2F_2 base chemistry eliminated previous CD bias
- => Much reduced selectivity (extreme sensitivity to C_4F_8 flow)

PAR-710 Resist
300 nm TERA

TERA Development F Open Etch Processes

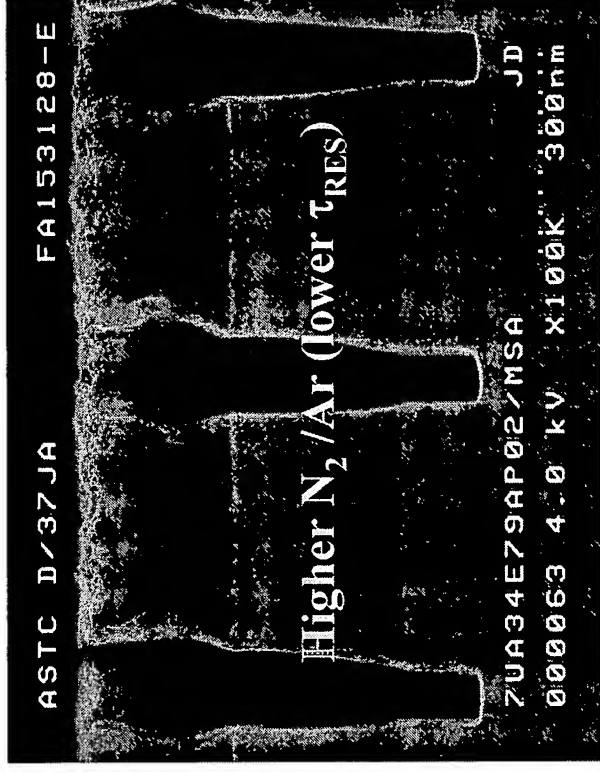


>2:1 selectivity
(200 nm PR + 80 nm Polymeric Cap)
-30 nm CD Bias (c/e similar)

TEL 85 Process:

SiC: 60 secs / 40 mT / 1.4kW / 5 C₄F₈ / 10 CH₂F₂ / 80 N₂ / 5 O₂ / 200 Ar

- => Reduce CH₂F₂ flow (less polymer)
- => Flatten profile (similar to earlier experiments)
- => Reduce CD Bias



>2:1 selectivity
(220 nm PR Remains)
-20 nm c CD Bias, -120 nm e CD Bias

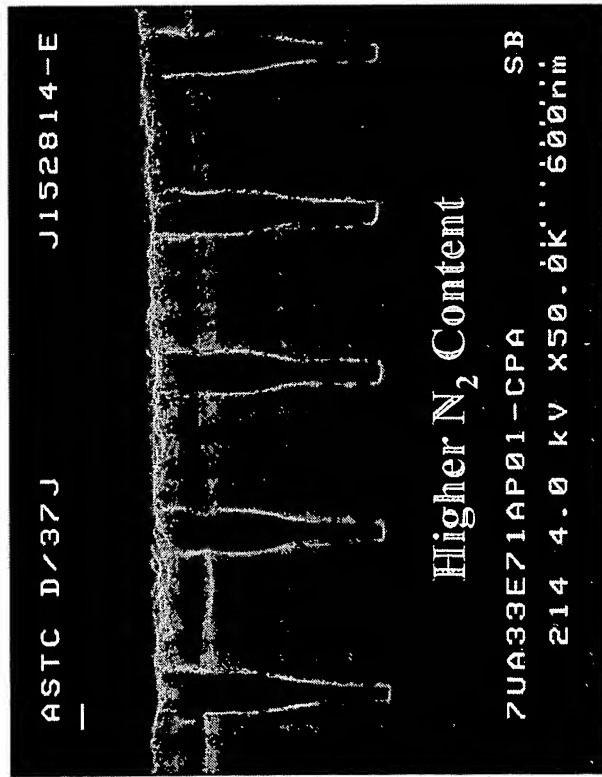
TEL 85 Process:

SiC: 60 secs / 40 mT / 1.4kW / 5 C₄F₈ / 10 CHF₃ / 100 N₂ / 5 O₂ / 250 Ar

- => Increase τ_{RES} (Ar/N₂ flow) (based on previous)
- => Flatten profile (similar to earlier experiments)
- => Reduce CD Bias

PAR-710 Resist
300 nm TERA

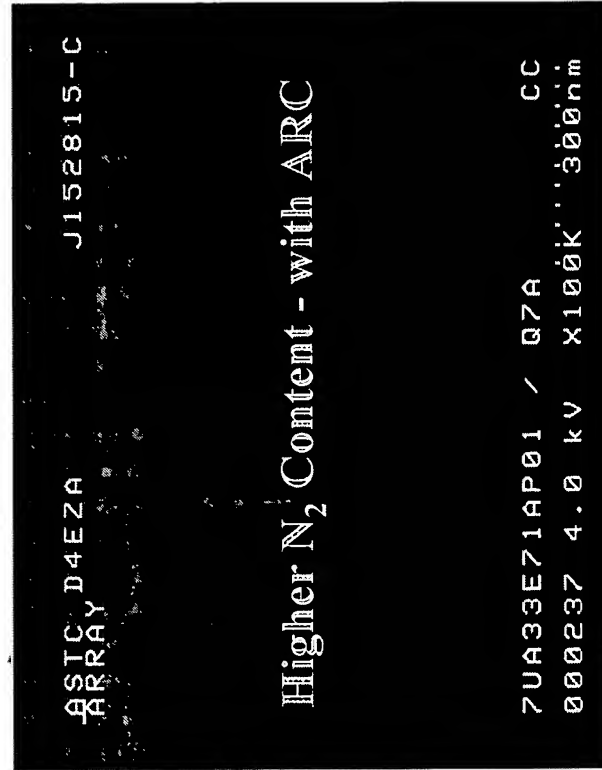
TERA Development F Open Etch Processes



>1.4:1 selectivity
(370 nm into BSG)
center just etch, low CD

TEL 85 Process:

SiC: 90 secs / 40 mT / 1.4kW / 5 C₄F₈ / 10 CHF₃ / 80 N₂ / 5 O₂ / 200 Ar



>1.4:1 selectivity
(190c, 300e nm into BSG)

TEL 85 Process:

ARC: 90 secs / 150 mT / 500 W / 10 O₂ / 500 Ar / 20 CH₂F₂

SiC: 90 secs / 40 mT / 1.4kW / 5 C₄F₈ / 10 CHF₃ / 80 N₂ / 5 O₂ / 200 Ar

- => Continue N₂ increase
- => Tune c/e overetch
- => Flatten profile (similar to earlier experiments)

**This Page is Inserted by IFW Indexing and Scanning
Operations and is not part of the Official Record**

BEST AVAILABLE IMAGES

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images include but are not limited to the items checked:

- ☐ BLACK BORDERS
- ☐ IMAGE CUT OFF AT TOP, BOTTOM OR SIDES
- ☐ FADED TEXT OR DRAWING
- ☐ BLURRED OR ILLEGIBLE TEXT OR DRAWING
- ☐ SKEWED/SLANTED IMAGES
- ☐ COLOR OR BLACK AND WHITE PHOTOGRAPHS
- ☐ GRAY SCALE DOCUMENTS
- ☐ LINES OR MARKS ON ORIGINAL DOCUMENT
- ☐ REFERENCE(S) OR EXHIBIT(S) SUBMITTED ARE POOR QUALITY
- ☐ OTHER: _____

IMAGES ARE BEST AVAILABLE COPY.

As rescanning these documents will not correct the image problems checked, please do not report these problems to the IFW Image Problem Mailbox.